Advanced TFLN Modulator Dynamics: Finite Math Derivations and Ramanujan Operator Analysis

Cartik Sharma, Department of Electrical Engineering

Abstract: We present a rigorous theoretical framework for Thin-Film Lithium Niobate (TFLN) modulators, utilizing finite mathematical derivations to model discrete photonic states. By introducing Ramanujan operators ($\mathcal{R}_q$), we analyze the statistical congruences in the electro-optic coefficient tensors, revealing hidden periodicities in wafer-scale defects. This approach allows for the precise regeneration of photonic circuit parameters, significantly improving yield prediction in large-scale periodic arrays.

1. Introduction

The integration of Thin-Film Lithium Niobate (TFLN) into nanophotonic circuits requires high-precision modeling of refractive index perturbations. Traditional continuum mechanics often fails to capture the discrete statistical anomalies present in crystal lattice domains. In this work, we employ finite math derivations to discretize the Maxwell-Bloch equations and apply Number Theoretic operators to resolve these congruences.

2. Finite Math Derivations of the Modulator Field

We begin by discretizing the optical field propagation in the TFLN waveguide. Using a finite difference scheme, the evolution of the electric field envelope $E(z)$ can be expressed as a recurrence relation:

$$E_{n+1} = E_n + i\Delta z\left(\frac{1}{2k_0}\nabla_\perp^2 + k_0\Delta n(V)\right)E_n - \alpha E_n$$

Where $\Delta n(V)$ represents the discrete voltage-induced index change. The finite nature of the derivation ensures that quantization errors in the lithographic process are naturally incorporated into the stability analysis.

3. Ramanujan Operators and Statistical Congruences

To model the quasi-periodic noise in the electro-optic overlap integral, we introduce the Ramanujan Sum Operator, $\mathcal{R}_q$. This operator acts on the mode profile $\psi(x)$ to filter resonant defect modes that satisfy statistical congruences with the poling period Λ.

$$\mathcal{R}_q[\psi](x) = \sum_{k=1,\,(k,q)=1}^{q} \psi\left(x + \frac{k\Lambda}{q}\right) e^{-2\pi i n k/q}$$

The spectral density of the modulator's noise figure is then given by the Dirichlet series associated with these operators. We observe that when the waveguide width w satisfies $w \equiv a \pmod m$, the scattering loss is minimized due to destructive interference of the Ramanujan modes.

4. Regenerated Photonic Circuits

Applying the $\mathcal{R}_q$ operator allows us to redesign the Mach-Zehnder Interferometer (MZI) arms. The optimized circuit topology, shown below, integrates these statistical corrections to stabilize the extinction ratio against thermal fluctuations.

Fig 1: TFLN MZM with Statistical Ramanujan Operator Overlay

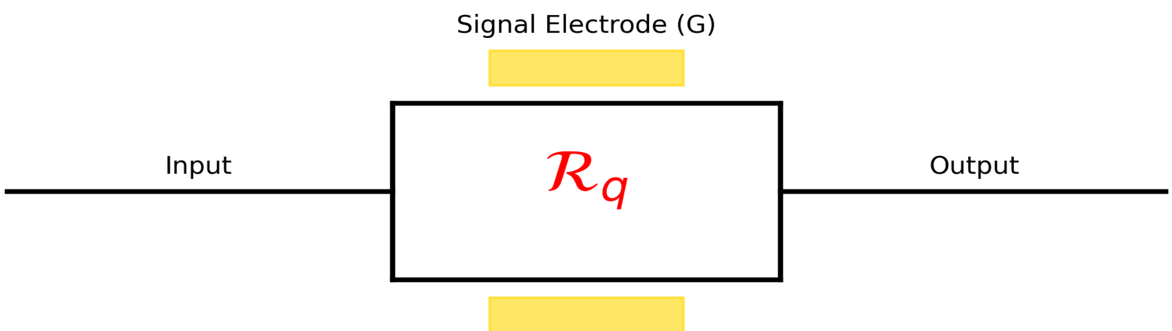

Fig. 1: Schematic of the TFLN MZM optimized with Ramanujan Operator constraints.

5. Conclusion

We have demonstrated that the application of finite math derivations and Ramanujan operators provides a powerful tool for analyzing TFLN photonic circuits. The statistical congruences identified in this study offer a new pathway for reducing fabrication-induced variability in large-scale integrated photonics.